# INTERNATIONAL STANDARD

# IEC 61131-2

Third edition 2007-07







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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

## PROGRAMMABLE CONTROLLERS -

# Part 2: Equipment requirements and tests

### **FOREWORD**

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International Standard IEC 61131-2 has been prepared by subcommittee 65B: Devices, of IEC technical committee 65: Industrial-process measurement and control.

This third edition of IEC 61131-2 cancels and replaces the second edition published in 2003 and constitutes a technical revision.

This third edition includes the following significant technical changes with respect to the previous edition.

- a) DC power port requirements have been moved from Clause 8 to Clause 5.
- b) Correction of the following tests of Clause 6:
  - · voltage range test;
  - fast supply voltage variation test;
  - slow supply voltage variation test;
  - gradual shut-down/start-up test.
- c) Change of EMC requirements in Clause 8:

- requirements for radiofrequency interference in Table 33 changed from 3 V to 10 V for Zone B equipment;
- reference to EMC basic standards with the last version;
- reference to generic standards 61000-6-x;
- cable length aligned to generic standards.
- d) Correction of the following tests in Clause 9:
  - voltage dips and interruptions power port type tests and verifications.
- e) New organization of Clause 11:
  - equipment types and protection;
  - open PLC-system equipment;
  - enclosed PLC-system equipment:
    - Class I equipment;
    - Class II equipment;
    - Class III equipment;
  - protection against electric shock;
  - definition of secondary circuits which do not pose a risk of electric shock:
    - Class 2 circuit:
    - limited voltage/current circuit;
    - limited voltage circuit,
    - limited energy circuit ≤30 V a.c. or 42,2 V peak;
    - limited impedance circuit;
  - protection against the spread of fire within limited power circuits;
  - potective earthing requirements for enclosed equipment;
  - minor improvements in different subclauses;
- tins://standa.els.iteh.impulse test only for verification of clearances.9313-670de584d63b/jec-61131-2-2007

The text of this standard is based on the following documents:

FDIS	Report on voting
65B/623/FDIS	65B/636/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The list of all parts of the IEC 61131 series, under the general title *Programmable controllers*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- · replaced by a revised edition, or
- · amended.

A bilingual version of this publication may be issued at a later date.

## INTRODUCTION

IEC 61131-2 is part of a series of standards on programmable controllers and the associated peripherals and should be read in conjunction with the other parts of the series.

Where a conflict exists between this and other IEC standards (except basic safety standards), the provisions of this standard should be considered to govern in the area of programmable controllers and their associated peripherals.

Compliance with IEC 61131-2 cannot be claimed unless the requirements of 7.2 are met.

Service and physical environment requirements are specified in Clause 4. Functional requirements are specified in Clause 5. Electromagnetic compatibility requirements are specified in Clause 8. Safety requirements are specified in Clause 11.

Terms of general use are defined in IEC 61131-1. More specific terms are defined in each part.

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